Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/626,574	MISHIMA ET AL.	
Examiner	Art Unit	
Christopher M. Keehan	1712	

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SEARCHED					
Class	Subclass	Date	Examiner		
428	413	4/11/2005	СМК		
	418				
	447				
	448				
	450				
	702				
524	441				
523	457				
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOT (INCLUDING SEARCH	ES Strategy)
	DATE	EXMR
EAST	4/11/2005	СМК
Inventor name search		
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